



US00D753002S

(12) **United States Design Patent**
Russell

(10) **Patent No.:** **US D753,002 S**

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(54) **DIAGNOSTIC CIRCUIT TEST DEVICE**

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(**) Term: **14 Years**

(21) Appl. No.: **29/514,629**

(22) Filed: **Jan. 14, 2015**

(51) **LOC (10) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/78**

(58) **Field of Classification Search**
USPC D10/78
CPC G01R 19/14; G01R 19/145; G01R 1/15;
G01R 19/155; G01R 1/07; G01R 1/06788;
G01R 1/06794; G01R 1/071; G01R 1/072;
G01R 1/067; G01R 1/06705; G01R 1/06711;
G01R 1/06733; G01R 1/06738; G01R
1/06744; G01R 1/0675; G01R 1/06

See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

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(57) **CLAIM**

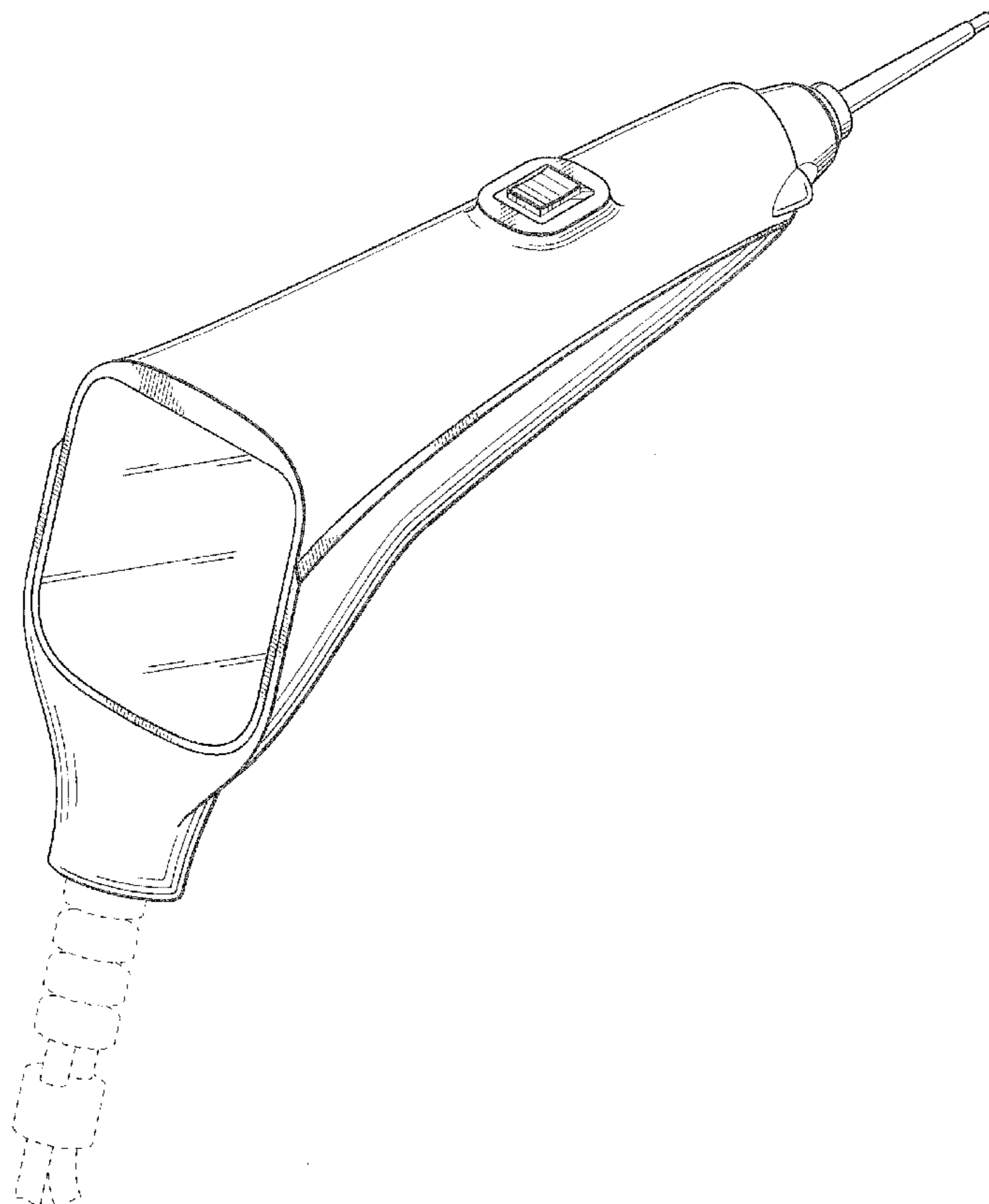
The ornamental design for an diagnostic circuit test device, as shown and described.

DESCRIPTION

FIG. 1 is a top, front, right side perspective view of the diagnostic circuit test device of the present invention; FIG. 2 is a left side elevation view, the right side elevation view being a mirror image; FIG. 3 is a front elevation view; FIG. 4 is a rear elevation view; FIG. 5 is a top plan view; and, FIG. 6 is a bottom plan view.

The broken lines of the bottom surface shown in the drawings views are included for the purpose of illustrating environmental structure and form no part of the claimed invention.

1 Claim, 4 Drawing Sheets



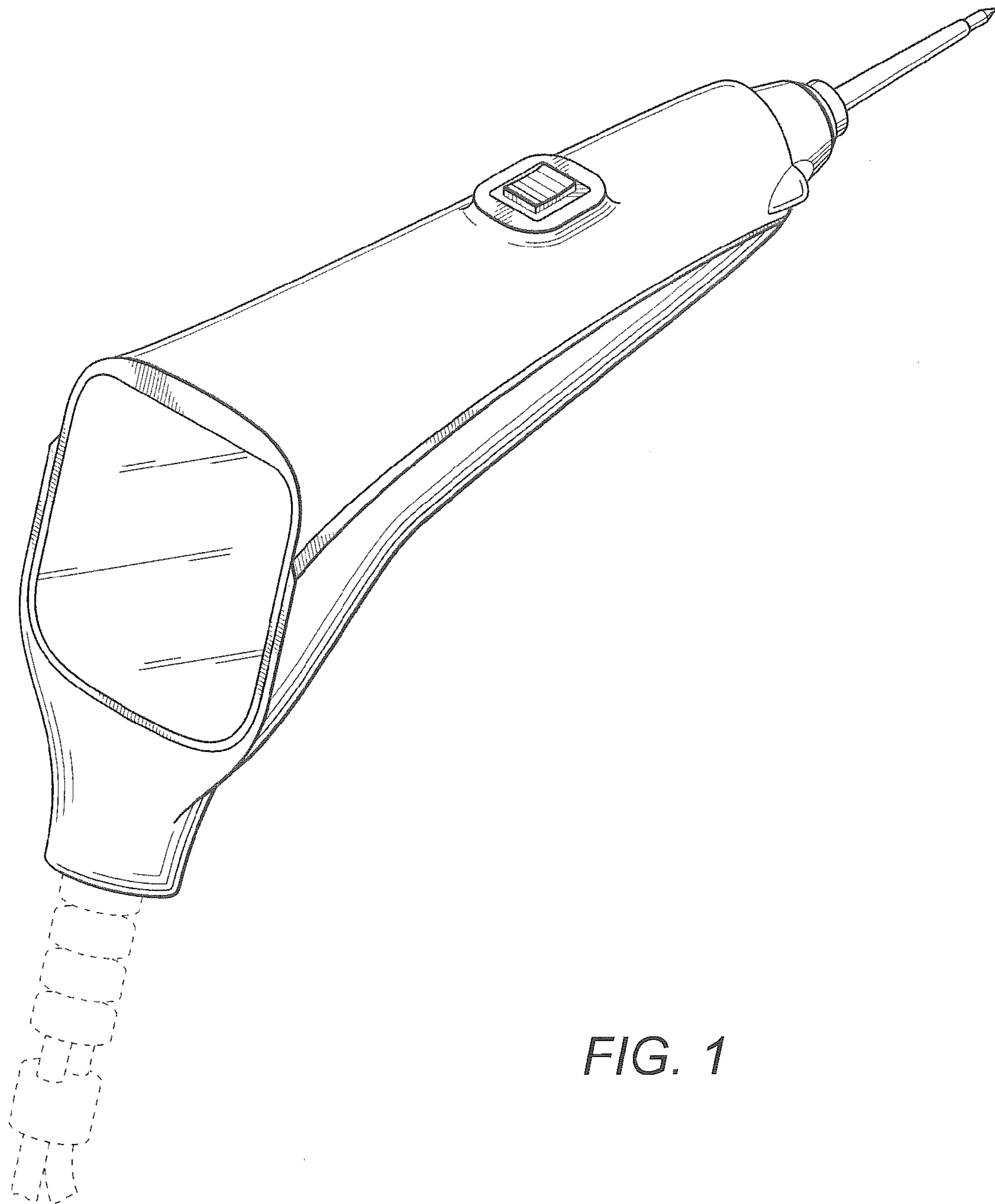


FIG. 1

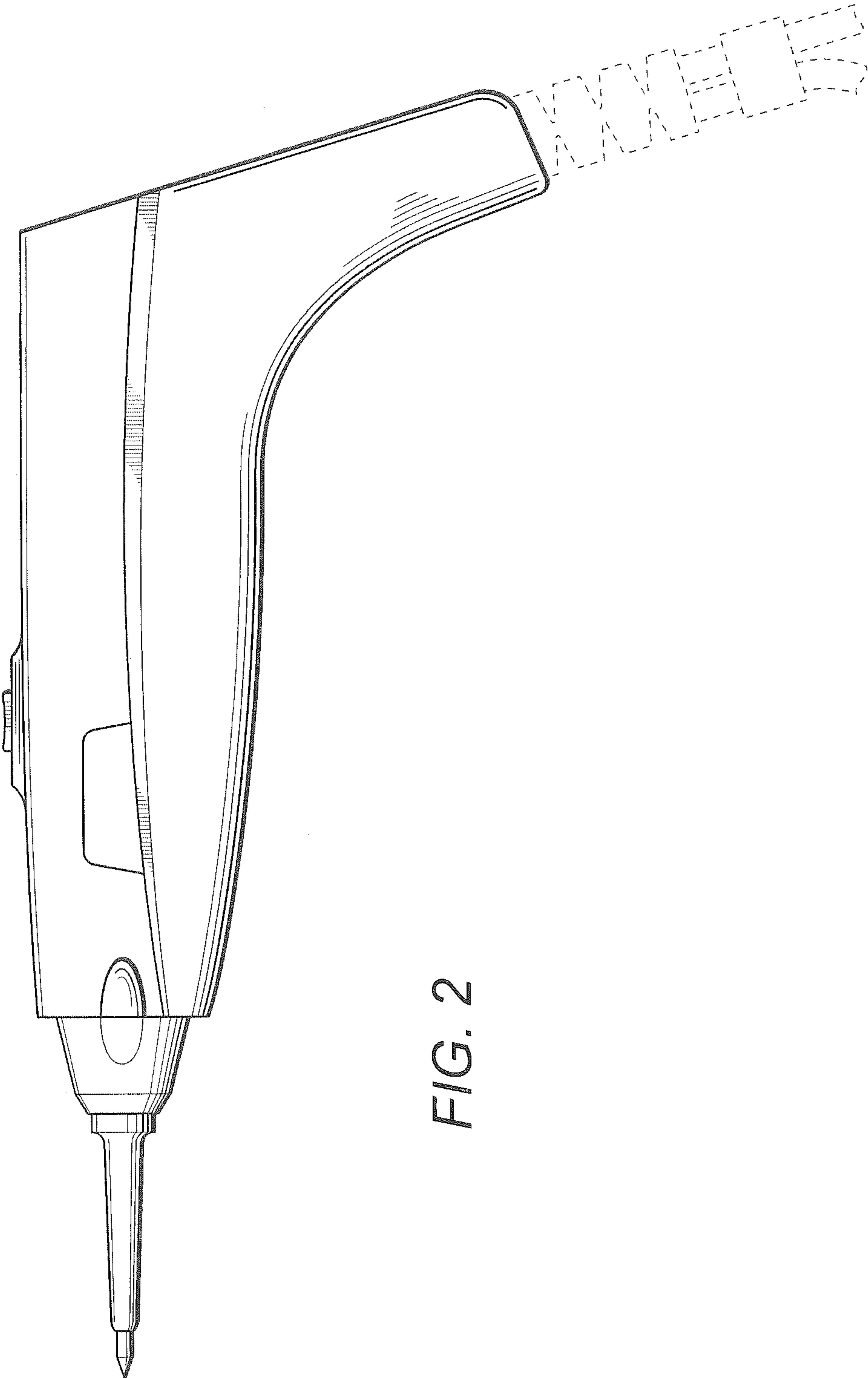


FIG. 2

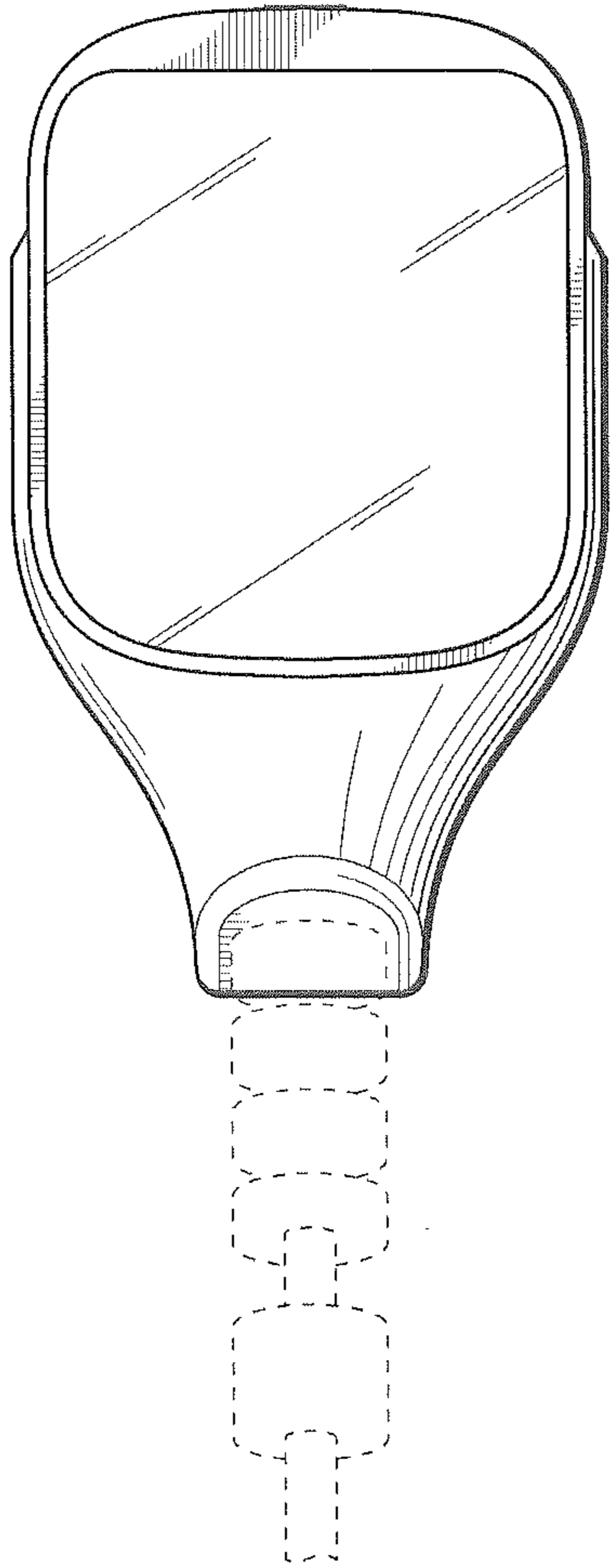


FIG. 3

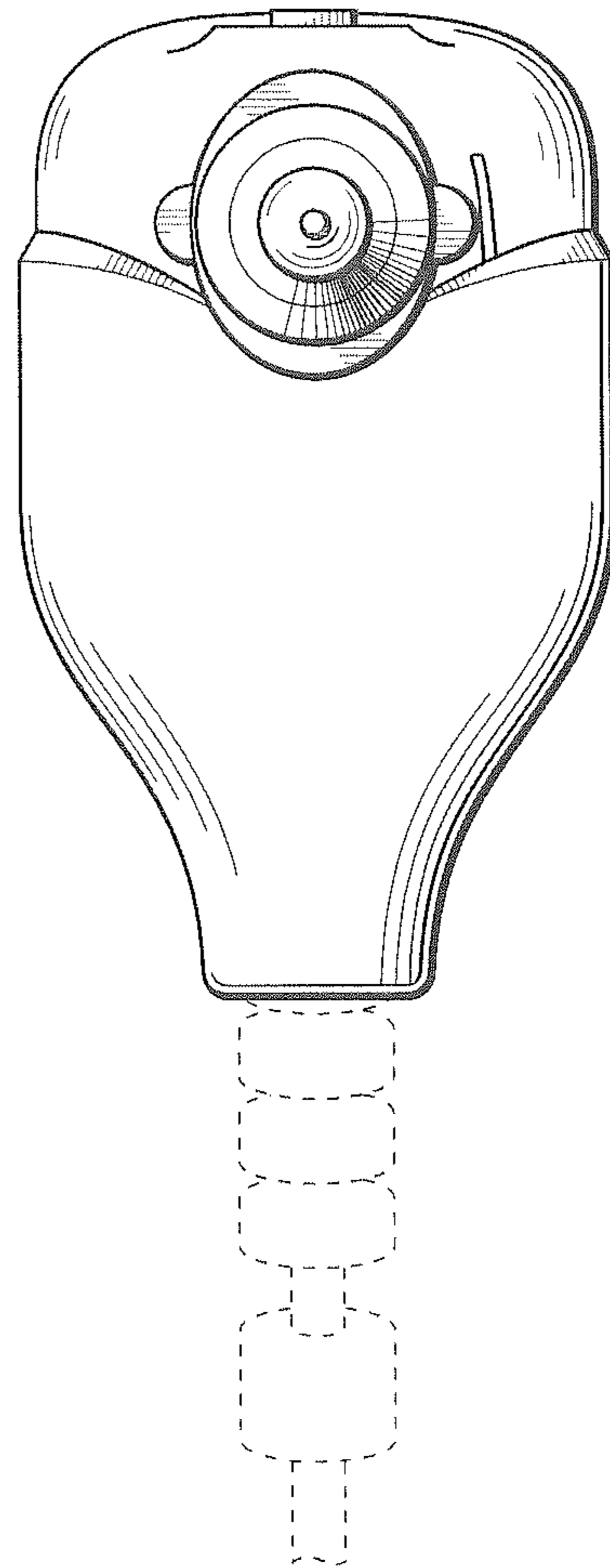


FIG. 4

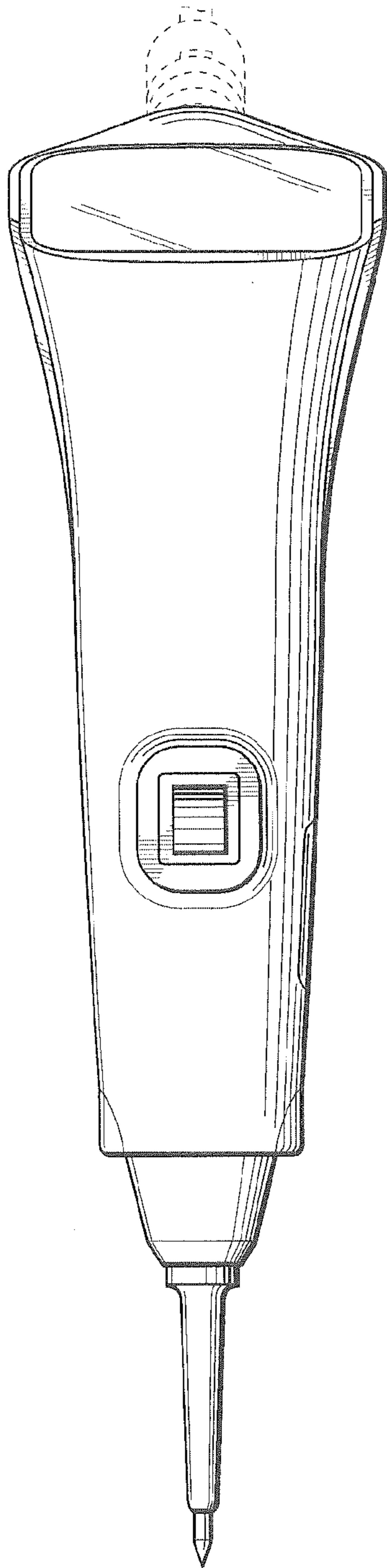


FIG. 5

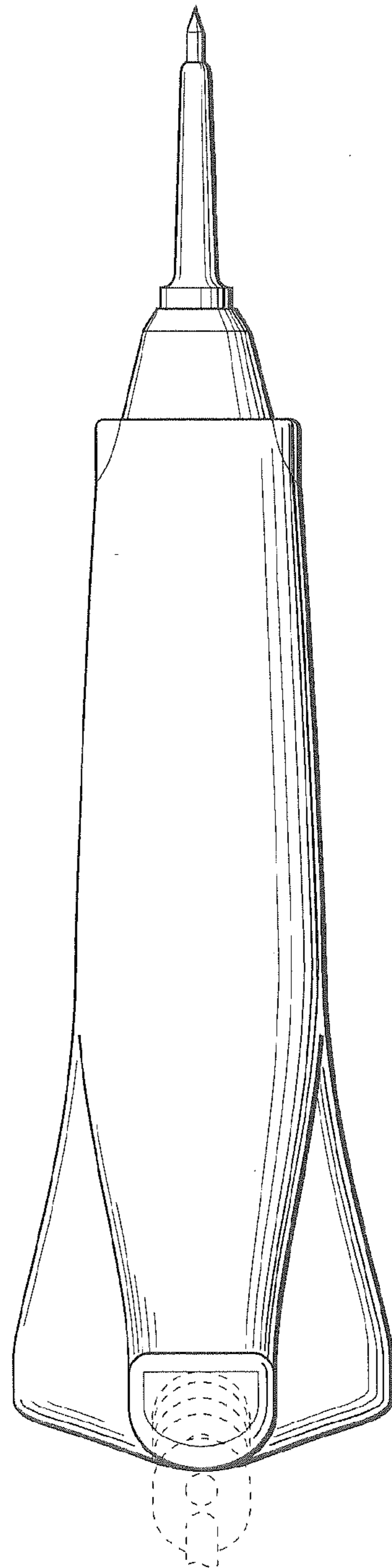


FIG. 6